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1. DMEA15B-001: Optimized Scintillator for High Resolution X-ray Imaging at 9keV

Release Date: 04-24-2015Open Date: 05-26-2015Due Date: 06-24-2015Close Date: 06-24-2015

Rapid Integrated Circuit (IC) inspection using x-ray microscopy requires novel x-ray scintillating materials with high efficiency and high spatial resolution. Current scintillator materials, such as Cesium Iodide (CsI), suffer from a trade-off between efficiency and spatial resolution. Novel materials with higher stopping power and light yields are necessary to address the stringent requirements o ...

STTR Defense Microelectronics ActivityDepartment of Defense

2. DMEA13B-001: Electrochemical Micro-Capacitors Utilizing Carbon Nanostructures

Release Date: 07-26-2013Open Date: 08-26-2013Due Date: 09-25-2013Close Date: 09-25-2013

TECHNOLOGY AREAS: Materials/Processes, Electronics The technology within this topic is restricted under the International Traffic in Arms Regulation (ITAR), which controls the export and import of defense-related material and services. Offerors must disclose any proposed use of foreign nationals, their country of origin, and what tasks each would accomplish in the statement of work in accordan ...

STTR Department of DefenseDefense Microelectronics Activity

3. DMEA122-001: High Speed, High Resolution X-ray System for Inspecting Integrated Circuits

Release Date: 04-24-2012Open Date: 05-24-2012Due Date: 06-27-2012Close Date: 06-27-2012

OBJECTIVE: Develop an affordable x-ray microscope system for use in performing integrated circuit (IC) reverse engineering. DESCRIPTION: X-ray microscopy using a synchrotron as the x-ray source has been demonstrated to be an extremely valuable tool in the performance of high throughput integrated circuit evaluation and reverse engineering efforts. However, synchrotron x-ray sources are prohi ...

SBIR Defense Microelectronics Activity

4. 001: Low Power Tri-axial Acoustic Sensor

Release Date: 04-29-2011Open Date: 05-12-2011Due Date: 06-28-2011Close Date: 06-28-2011

The U.S. Customs and Border Protection (CBP) use UGS units to detect personnel, vehicles, and aircraft engaged in illegal activity at the U.S. border. The UGS units consist of: sensor(s) for detecting activity; a buried housing that contains a processing unit that interprets the received signals from the sensor(s) and performs administrative and control tasks; a radio for communicating alarms back ...

SBIR Science and Technology Directorate

5. 002: Improved Wipes for Surface Sampling of Chemical Agents on Porous Materials

Release Date: 04-29-2011Open Date: 05-12-2011Due Date: 06-28-2011Close Date: 06-28-2011

The Department of Homeland Security (DHS) has a need for a novel surface wipe material that more efficiently removes low volatility chemical agent contamination from porous and absorptive surfaces (e.g., uncoated and coated concrete, painted wallboard, unglazed ceramic tile) than current cellulosic-based, gauze-type, wipe materials. The novel wipe material will further demonstrate the ability to q ...

SBIR Science and Technology Directorate

6. 003: Mobile Device Forensics

Release Date: 04-29-2011Open Date: 05-12-2011Due Date: 06-28-2011Close Date: 06-28-2011

Within the area of mobile device forensics, the Department of Homeland Security (DHS) Science and Technology (S&T) Directorate is currently interested in three distinct facets of this complex problem area. Proposers can respond to any of the three sub-topics listed below (i.e., proposers may submit up to three different sub-topic proposals in response to this mobile device forensics topic). Sub-t ...

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7. 004: Short Standoff Checkpoint Detection System for Explosives

Release Date: 04-29-2011Open Date: 05-12-2011Due Date: 06-28-2011Close Date: 06-28-2011

Checkpoint security incorporates a wide variety of screening technologies and processes to detect person-borne threats and illicit objects, including weapons and explosives. Individuals attempting to circumvent checkpoint security have resorted to a variety of techniques to avoid detection, including hiding threat or illicit objects, but minute quantities of trace explosives may remain on their pe ...

SBIR Science and Technology Directorate

8. 005: Iris Image Quality Tool Suite for Biometric Recognition

Release Date: 04-29-2011Open Date: 05-12-2011Due Date: 06-28-2011Close Date: 06-28-2011

Biometric system performance depends on the quality of the acquired input samples. If sample quality can be improved, whether by sensor design, user interface design, or standards compliance, better performance can be realized. For those aspects of quality that cannot be designed-in, an ability to analyze the image and identify recognition-related defects and problems is needed. The ability to qui ...

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9. 006: Intelligent “Object” Symbology

Release Date: 04-29-2011Open Date: 05-12-2011Due Date: 06-28-2011Close Date: 06-28-2011

The Department of Homeland Security (DHS) is committed to using cutting- edge technologies and scientific talent in its quest to make America safer. The International Committee for Information Technology Standards (ANSI INCITS) 415-2006, Homeland Security Mapping Standard - Point Symbology for Emergency Management establishes point symbols focused exclusively on the emergency management and emerge ...

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